

TLV3511 レール ツー レール入力の 7ns 高速コンパレータ

1 特長

- 伝搬遅延:6ns
- 高いトグル周波数:180MHz
- 幅広い電源電圧範囲:2.7V~5.5V
- 入力オフセット電圧:±1mV (標準値)
- 低い消費電流:1.1mA (チャネルあたり)
- 各レールから 300mV 拡張された入力電圧同相範囲
- 内部ヒステリシス:2.3 mV
- 既知の起動条件を提供するパワーオンリセット
- プッシュプル出力
- 温度範囲:-40℃~+125℃

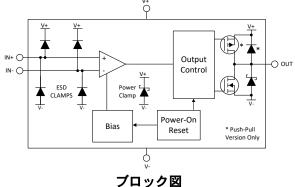
2 アプリケーション

- モータードライブの診断とモニタリング
- サーボドライブ制御モジュール
- サーボドライブ位置センサ
- 医療/ヘルスケア
- フィールドトランスミッタとセンサ

3 概要

TLV351x は、プッシュプル出力を搭載した 5V シングル およびデュアル チャネル コンパレータのファミリです。この ファミリは速度と消費電力の組み合わせが非常に優れて おり、伝搬遅延は 7ns、電源電圧範囲は 2.7V~5.5V で、チャネルあたりの静止電流はわずか 1mA です。

すべてのデバイスに、パワーオン リセット (POR) 機能が 搭載されています。これにより、出力が入力に応答する



前、最小電源電圧に達するまでの間、出力が既知の状態 (出力 Low) であることが保証されるため、システムの電源 オンおよび電源オフ時に誤った出力が発生することを防 止できます。

同様に、TLV351x は標準のリード付きおよびリードレス パ ッケージで供給され、レールツーレール入力、低オフセッ ト電圧、大きな出力駆動電流などの特長があります。これ らの特長と高速な応答時間により、本コンパレータは電流 センシング、ゼロクロス検出、その他精度と速度が重要な さまざまなアプリケーションに最適です。

すべてのデバイスは、-40°C~125°C°C の拡張工業用温 度範囲で仕様が規定されています。

製品情報

部品番号	パッケージ ⁽¹⁾	本体サイズ (公称) ⁽²⁾
TLV3511	SC-70 (5)	1.25mm × 2.00mm
	SOT-23 (5) (プレビュ ー)	1.60mm × 2.90mm
	SOT (5) (プレビュー)	1.2mm × 1.5mm
TLV3512	VSSOP (8) (プレビュ ー)	3.00mm × 3.00mm
	WSON (8) (プレビュー)	2.00mm × 2.00mm

- (1) 利用可能なすべてのパッケージについては、データシートの末尾 にある注文情報を参照してください。
- パッケージ サイズ (長さ×幅) は公称値で、該当する場合はピンも (2) 含まれます。

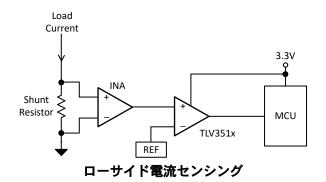




Table of Contents

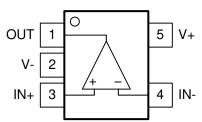
4 柱目
1 特長
2 アプリケーション
3 概要
4 Pin Configuration and Functions
Pin Configurations: TLV3511 and TLV3512
5 Specifications
5.1 Absolute Maximum Ratings
5.2 ESD Ratings
5.3 Recommended Operating Conditions
5.4 Thermal Information
5.5 Electrical Characteristics
5.6 Switching Characteristics
5.7 Typical Characteristics
6 Detailed Description
6.1 Overview1
6.2 Functional Block Diagrams1
6.3 Feature Description1

6.4 Device Functional Modes	12
7 Application and Implementation	14
7.1 Application Information	
7.2 Typical Applications	17
7.3 Power Supply Recommendations	18
7.4 Layout	
8 Device and Documentation Support	19
8.1 Documentation Support	
8.2ドキュメントの更新通知を受け取る方法	
8.3 サポート・リソース	20
8.4 Trademarks	
8.5 静電気放電に関する注意事項	20
8.6 用語集	20
9 Revision History	
10 Mechanical, Packaging, and Orderable	
Information	20



4 Pin Configuration and Functions

Pin Configurations: TLV3511 and TLV3512



DCK, DBV, DRL Packages SC70, SOT-23-5, SOT Top View (Standard "north west" pinout)

表 4-1. Pin Functions: TLV3511

PIN		1/0	DESCRIPTION		
NAME	NO.	I/O	DESCRIPTION		
OUT	1	0	Output		
V-	2	-	Negative supply voltage		
IN+	3	I	Non-inverting (+) input		
IN-	4	I	Inverting (-) input		
V+	5	-	Positive supply voltage		

English Data Sheet: SNOSDJ9



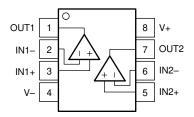


図 4-1. DGK Package 8-Pin VSSOP Top View

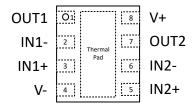


図 4-2. DSG Package 8-Pin WSON Top View

Pin Functions: TLV3512

i	PIN		DESCRIPTION
NAME	NO.	I/O	DESCRIPTION
IN1+	1	ı	Noninverting input, channel 1
IN1-	2	I	Inverting input, channel 1
IN2-	3	I	Inverting input, channel 2
IN2+	4	I	Noninverting input, channel 2
OUT1	7	0	Output, channel 1
OUT2	6	0	Output, channel 2
V-	5	-	Negative (lowest) supply or ground
V+	8	-	Positive (highest) supply

English Data Sheet: SNOSDJ9



5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

	MIN	MAX	UNIT
Supply voltage V _S = (V+) - (V-)		6	V
Differential input voltage, VID	-6	6	V
Input pins (IN+, IN-) from (V-) (2)	- 0.5	(V+) + 0.5	V
Current into input pins (IN+, IN-)	-10	10	mA
Output (OUT) from (V-)	- 0.5	(V+) + 0.5	V
Output short-circuit current	-100	100	mA
Output short-circuit duration		10	S
Junction temperature, T _J		150	°C
Storage temperature, T _{stg}	-65	150	°C

- (1) Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) Input terminals are diode-clamped to (V–) and (V+). Input signals that can swing more than 0.5V beyond the supply rails must be current-limited to 10mA or less.

5.2 ESD Ratings

			VALUE	UNIT
V _(ESD)	Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	±2000	V
V _(ESD)	Electrostatic discharge	Charged-device model (CDM), per JEDEC specification JESD22-C101 ⁽²⁾	±1000	V

- (1) JEDEC document JEP155 states that 500V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250V CDM allows safe manufacturing with a standard ESD control process.

5.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

	MIN	MAX	UNIT
	IVIIIN	IVIAA	UNII
Supply voltage $V_S = (V+) - (V-)$	2.7	5.5	V
Input voltage range	(V-) - 0.3	(V+) + 0.3	V
Ambient temperature, T _A	-40	125	°C

5.4 Thermal Information

THERMAL METRIC (1)		TLV	TLV3511			
		DBV (SOT-23)	DCK (SC70)	UNIT		
		5 PINS	5 PINS			
R _{0JA}	Junction-to-ambient thermal resistance	198.1	220.1	°C/W		
R _{0JC(top)}	Junction-to-case (top) thermal resistance	95.6	136.5	°C/W		
R _{0JB} Junction-to-board thermal resistance		64.7	65.9	°C/W		
Ψ_{JT}	Junction-to-top characterization parameter	32.1	34.5	°C/W		
Ψ_{JB}	Junction-to-board characterization parameter	64.3	65.4	°C/W		
R _{0JC(bot)}	Junction-to-case (bottom) thermal resistance	n/a	n/a	°C/W		

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.



5.5 Electrical Characteristics

 V_S = 2.7V to 5V, V_{CM} = V_S / 2; at T_A = 25°C (unless otherwise noted). Typical values are at T_A = 25°C.

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
DC Input Cha	aracteristics					
V _{IO}	Input Offset Voltage	$V_S = 5V$, $V_{CM} = V_S / 2$		±1	±5	mV
V _{IO}	Input Offset Voltage	$V_S = 5V$, $V_{CM} = V_S / 2$, $T_A = -40$ to $125^{\circ}C$			±6	mV
V _{HYS}	Hysteresis	$V_{S} = 5V, V_{CM} = V_{S} / 2$		2.3		mV
V _{HYS}	Hysteresis	$V_S = 5V$, $V_{CM} = V_S / 2$, $T_A = -40$ to $125^{\circ}C$			3.5	mV
V _{CM}	Common-mode voltage range		(V-) - 0.2		(V+) + 0.2	V
I _B	Input bias current	$V_S = 5V$, $V_{CM} = V_S / 2$, $T_A = -40$ to $125^{\circ}C$			1.5	nA
I _{os}	Input offset current	$V_{S} = 5V, V_{CM} = V_{S} / 2$			10	pА
C _{IN}	Input capacitance			4		pF
CMRR	Common-mode rejection ratio	V _{CM} = V _{EE} - 0.2V to V _{CC} + 0.2V		80		dB
DC Output C	haracteristics				•	
V _{OH}	Voltage swing from (V+)	V _S = 5V, I _{Source} = 4mA		120	225	mV
V _{OH}	Voltage swing from (V+)	$V_S = 5V$, $I_{Source} = 4mA$, -40 to 125C			250	mV
V _{OL}	Voltage swing from (V-)	$V_S = 5V$, $I_{Sink} = 4mA$		140	225	mV
V _{OL}	Voltage swing from (V-)	$V_S = 5V$, $I_{Sink} = 4mA$, -40 to 125C			250	mV
I _{SC}	Short-circuit current	V _S = 5V, sourcing		75		mA
isc	Short-circuit current	V _S = 5V, sinking		85		IIIA
Power Suppl	у					
IQ	Supply current / Channel	V_S = 2.7V and 5V, no load, output low, T_A = -40 to 125°C		1.1	2	mA
V _{POR (postive)}	Power-On Reset Voltage			2.2		V
PSRR	Power Supply Rejection Ratio	V _S = 2.7V to 5.5V, T _A = -40 to 125°C		93		dB

5.6 Switching Characteristics

For $V_S = 2.7V$ to $V_S = 5V$, $V_{CM} = V_S / 2$; $C_L = 15pF$ at $T_A = 25^{\circ}C$ (Unless otherwise noted)

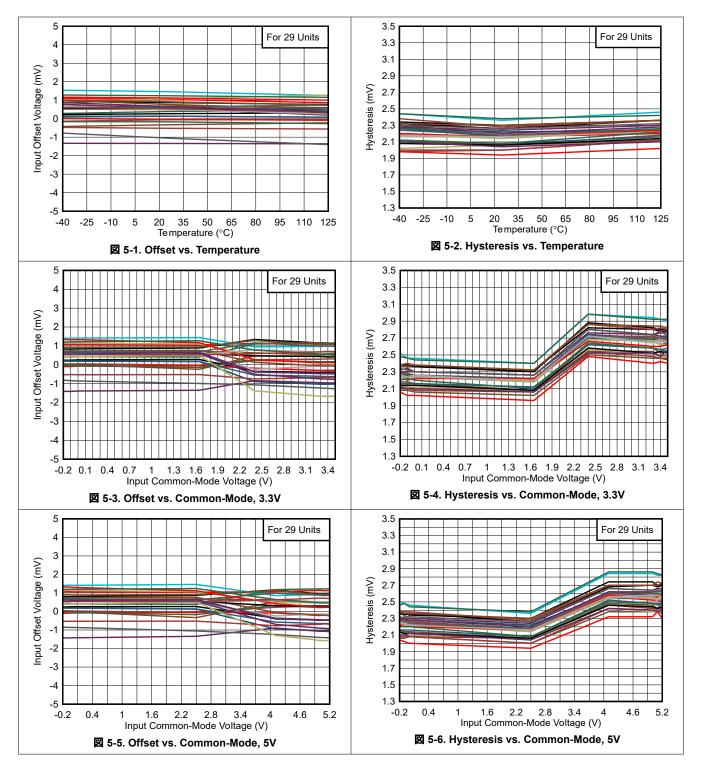
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PHL}	Propagation delay time, high to- low	Midpoint of input to midpoint of output, V _{OD} = 10mV		10		ns
t _{PHL}	Propagation delay time, high to- low	Midpoint of input to midpoint of output, V _{OD} = 50mV		6	7	ns
t _{PLH}	Propagation delay time, low-to high	Midpoint of input to midpoint of output, V _{OD} = 10mV		10		ns
t _{PLH}	Propagation delay time, low-to high	Midpoint of input to midpoint of output, V _{OD} = 50mV		6	7	ns
t _{PD} Skew	Propagation delay skew	Measured as absolute value of the difference between t _{PDLH} and t _{PDHL}		300		ps
PWin	Minimum input pulse width	Voverdrive = Vunderdrive = 50mV PWout = 90% of PWin		3.5		ns
f _{TOGGLE}	Input toggle frequency	V_{IN} = 200mV _{PP} Sine Wave, When output high reaches 90% of V _{CC} - V _{EE} or output low reaches 10% of V _{CC} - V _{EE}		180		MHz
t _R	Rise time	Measured from 20% to 80%		1		ns
t _F	Fall time	Measured from 20% to 80%		1		ns
t _{ON}	Power-up time	During power on, (V+) must exceed 2.2V for 2.1µs before the output will reflect the input.		2.1		μs

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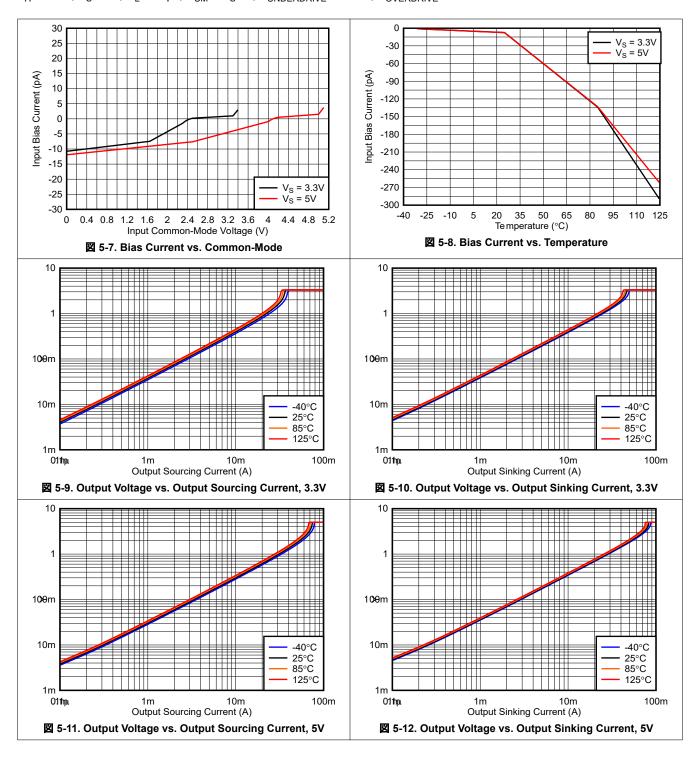
5.7 Typical Characteristics

 $T_A = 25$ °C, $V_S = 5$ V, $C_L = 15$ pF, $V_{CM} = V_S/2$ V, $V_{UNDERDRIVE} = 50$ mV, $V_{OVERDRIVE} = 50$ mV unless otherwise noted.



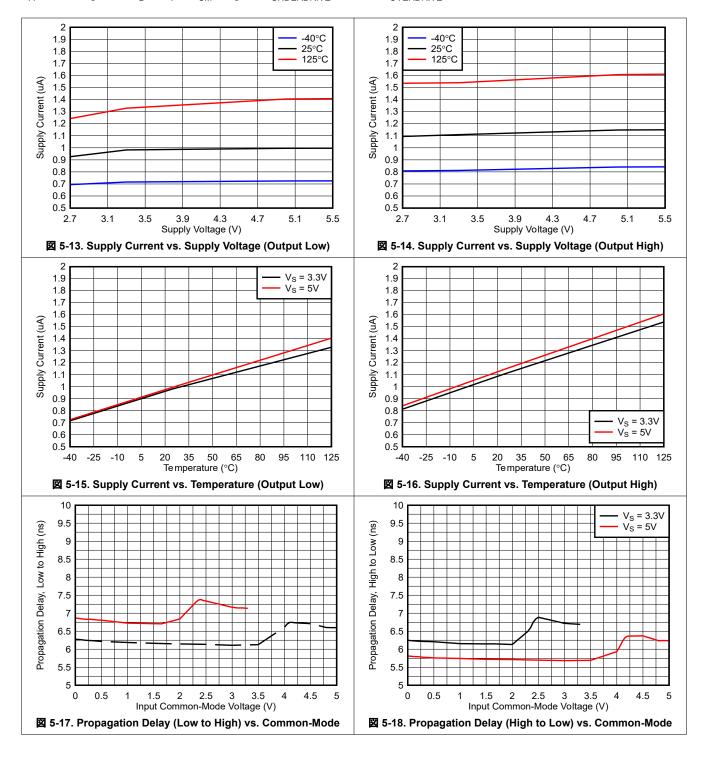


 $T_A = 25^{\circ}C$, $V_S = 5V$, $C_L = 15pF$, $V_{CM} = V_S/2V$, $V_{UNDERDRIVE} = 50mV$, $V_{OVERDRIVE} = 50mV$ unless otherwise noted.



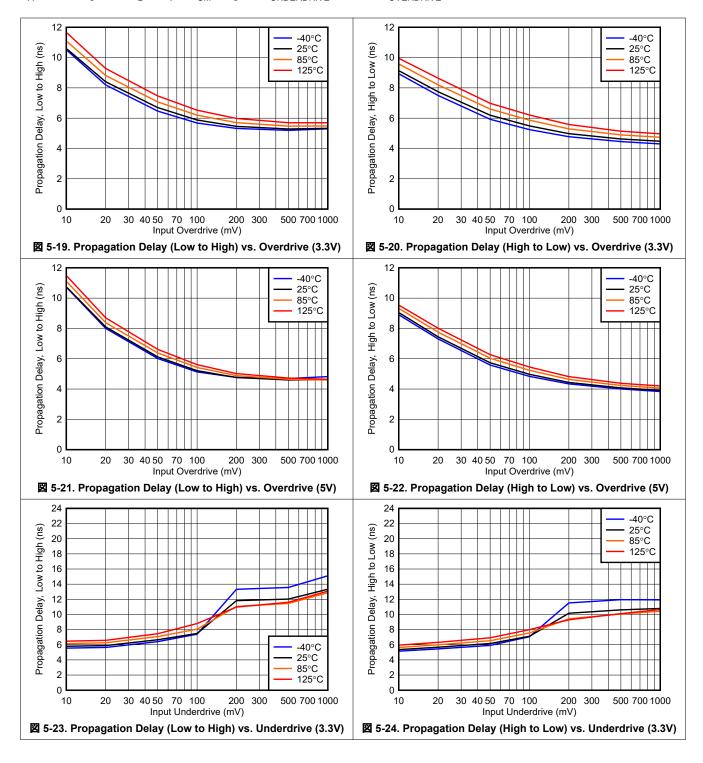


 $T_{A} = 25^{\circ}\text{C}, \ V_{S} = 5\text{V}, \ C_{L} = 15\text{pF}, \ V_{CM} = V_{S}/2\text{V}, \ V_{UNDERDRIVE} = 50\text{mV}, \ V_{OVERDRIVE} = 50\text{mV} \ unless otherwise noted.}$



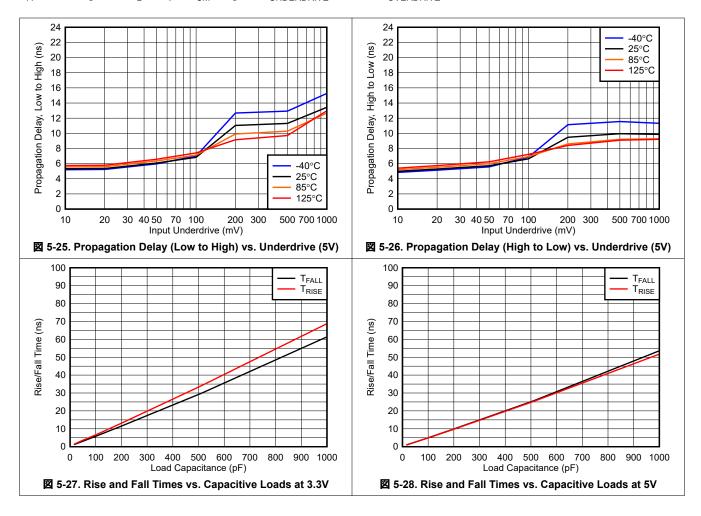


 $T_A = 25^{\circ}C$, $V_S = 5V$, $C_L = 15pF$, $V_{CM} = V_S/2V$, $V_{UNDERDRIVE} = 50mV$, $V_{OVERDRIVE} = 50mV$ unless otherwise noted.





 $T_A = 25^{\circ}C$, $V_S = 5V$, $C_L = 15pF$, $V_{CM} = V_S/2V$, $V_{UNDERDRIVE} = 50mV$, $V_{OVERDRIVE} = 50mV$ unless otherwise noted.





6 Detailed Description

6.1 Overview

The TLV351x devices are high-speed comparators consuming 1mA per channel with 7ns of propagation delay. The TLV351x detects fast voltage and current transients while maintaining low power consumption with single-ended, push-pull outputs

6.2 Functional Block Diagrams

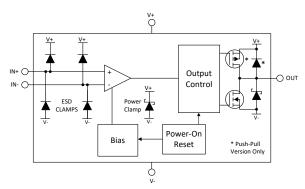


図 6-1. Block Diagram

6.3 Feature Description

The TLV351x comparators feature rail-to-rail inputs with integrated hysteresis, single-ended, push-pull outputs, and a Power-ON-Reset function.

6.4 Device Functional Modes

6.4.1 Inputs

The inputs incorporate internal ESD protection circuits to (V+) and (V-). Voltages on the inputs are limited to 0.3V beyond the rails.

When connecting to a low impedance source such as a power supply or buffered reference line, TI recommends adding a current-limiting resistor in series with the input to limit any transient currents if the clamps conduct. Limit the current to 10mA or less. One form of series resistance is any resistive input dividers or networks.

6.4.1.1 Unused Inputs

If a channel is not to be used, DO NOT tie the inputs together. Due to the high equivalent bandwidth and low offset voltage, tying the inputs directly together can cause high frequency oscillations as the device triggers on it's own internal wideband noise. Instead, the inputs can be tied to any available voltage that resides within the specified input voltage range and provides a minimum of 50mV differential voltage. For example, one input can be grounded and the other input connected to a reference voltage, or even (V+).

6.4.2 Internal Hysteresis

The device hysteresis transfer curve is shown below. This curve is a function of three components: V_{TH} , V_{OS} , and V_{HYST} :

- V_{TH} is the actual set voltage or threshold trip voltage.
- V_{OS} is the internal offset voltage between V_{IN+} and V_{IN-}. This voltage is added to V_{TH} to form the actual trip
 point at which the comparator must respond to change output states.
- V_{HYST} is the internal hysteresis (or trip window) that is designed to reduce comparator sensitivity to noise.
 (typically 2mV for the TLV351x family)



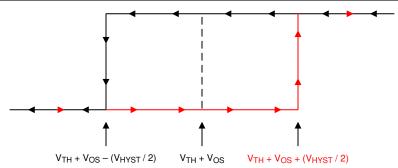


図 6-2. Hysteresis Transfer Curve

6.4.3 Outputs

The TLV351x features a push-pull output stage capable of both sinking and sourcing current. This allows driving loads such as LED's and MOSFET gates, as well as eliminating the need for a power-wasting external pull-up resistor. The push-pull output must never be connected to another output.

Directly shorting the output to the supply rails ((V+) when output "low" or (V-) when output "High") can result in thermal runaway and eventual device destruction. If output shorts are possible, a series current limiting resistor is recommended to limit the power dissipation.

Unused push-pull outputs must be left floating, and never tied to a supply, ground, or another output.

6.4.4 ESD Protection

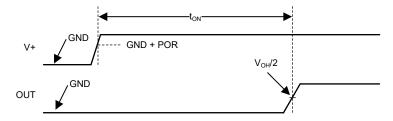
The inputs and outputs incorporate internal ESD protection circuits to (V+) and (V-).

Voltages on the inputs are limited to 0.3V beyond the rails. If the inputs are to be connected to a low impedance source, such as a power supply or buffered reference line, TI recommends adding a current-limiting resistor in series with the input to limit any transient currents in case the clamps conduct. Limit the current to 10mA or less.

6.4.5 Power-On Reset (POR)

The TLV351x devices have an internal Power-on-Reset (POR) circuit for known start-up or power-down conditions. While the power supply (V+) is ramping up or ramping down, the POR circuitry is active for up to 2.1us after the V_{POR} of 2.2V is crossed. When the supply voltage is equal to or greater than the minimum supply voltage, and after the delay period, the comparator output reflects the state of the differential input (V_{ID}).

For the TLV351x devices, the output is held low during the POR period (ton) as shown below.



☑ 6-3. Power-On Reset Timing Diagram

13



7 Application and Implementation

注

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

7.1 Application Information

7.1.1 Basic Comparator Definitions

7.1.1.1 Operation

The basic comparator compares the input voltage (V_{IN}) on one input to a reference voltage (V_{REF}) on the other input. In the example below, if V_{IN} is less than V_{REF} , the output voltage (V_O) is logic low (V_{OL}) . If V_{IN} is greater than V_{REF} , the output voltage (V_O) is at logic high (V_{OH}) . Likewise, the table below summarizes the output conditions. The output logic can be inverted by simply swapping the input pins.

表 7-1. Output Conditions

Inputs Condition	Output
IN+ > IN-	HIGH (V _{OH})
IN+ = IN-	Indeterminate (chatters - see Hysteresis)
IN+ < IN-	LOW (V _{OL})

7.1.1.2 Propagation Delay

There is a delay between from when the input crosses the reference voltage and the output responds. This is called the Propagation Delay. Propagation delay can be different between high-to low and low-to-high input transitions. This is shown as t_{pLH} and t_{pHL} in the figure below and is measured from the mid-point of the input to the midpoint of the output.

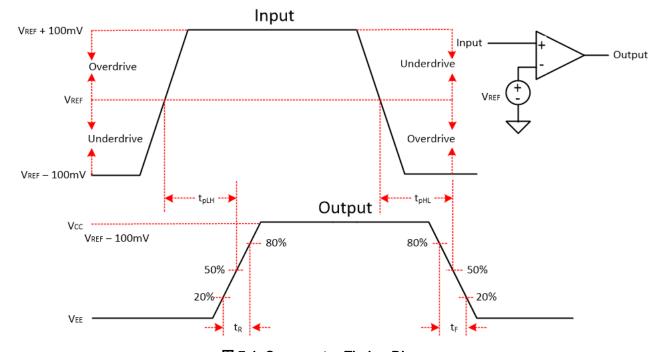


図 7-1. Comparator Timing Diagram

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7.1.1.3 Overdrive Voltage

The overdrive voltage, V_{OD} , is the amount of input voltage beyond the reference voltage (and not the total input peak-to-peak voltage). The overdrive voltage is 100mV as shown in the above example. The overdrive voltage can influence the propagation delay (t_p). The smaller the overdrive voltage, the longer the propagation delay, particularly when <100mV. If the fastest speeds are desired, it is recommended to apply the highest amount of overdrive possible.

The risetime (t_r) and falltime (t_f) is the time from the 20% and 80% points of the output waveform.

7.1.2 Hysteresis

The basic comparator configuration frequently produces a noisy "chatter" output if the applied differential input voltage is near the comparator's offset voltage. This usually occurs when the input signal is moving very slowly across the switching threshold of the comparator. This problem can be prevented by adding external hysteresis to the comparator.

Since the TLV351x only have a minimal amount of internal hysteresis of 2mV, external hysteresis can be applied in the form of a positive feedback loop that adjusts the trip point of the comparator depending on the current output state.

The hysteresis transfer curve is shown below. This curve is a function of three components: V_{TH} , V_{OS} , and V_{HYST} :

- V_{TH} is the actual set voltage or threshold trip voltage.
- V_{OS} is the internal offset voltage between V_{IN+} and V_{IN-}. This voltage is added to V_{TH} to form the actual trip
 point at which the comparator must respond to change output states.
- V_{HYST} is the hysteresis (or trip window) that is designed to reduce comparator sensitivity to noise.

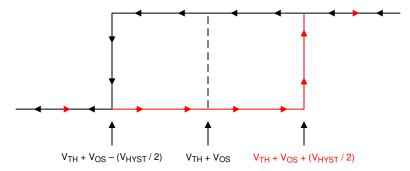


図 7-2. Hysteresis Transfer Curve

For more information, please see Application Note SBOA219 "Comparator with and without hysteresis circuit".

7.1.2.1 Inverting Comparator With Hysteresis

The inverting comparator with hysteresis requires a three-resistor network that is referenced to the comparator supply voltage (V_{CC}) , as shown below.

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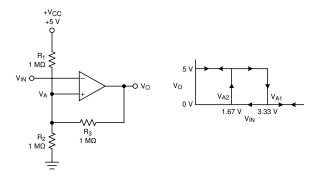


図 7-3. TLV351x in an Inverting Configuration With Hysteresis

The equivalent resistor networks when the output is high and low are shown below.

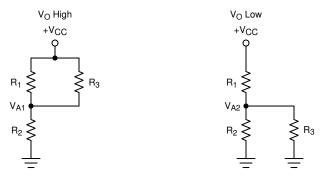


図 7-4. Inverting Configuration Resistor Equivalent Networks

When V_{IN} is less than V_A , the output voltage is high (for simplicity, assume V_O switches as high as V_{CC}). The three network resistors can be represented as R1 || R3 in series with R2, as shown above on the left.

The equation below defines the high-to-low trip voltage (V_{A1}).

$$V_{A1} = V_{CC} \times \frac{R2}{(R1 \parallel R3) + R2}$$
 (1)

When V_{IN} is greater than V_A , the output voltage is low. In this case, the three network resistors can be presented as R2 || R3 in series with R1, as shown above on the right.

Use equation below to define the low to high trip voltage (V_{A2}) .

$$V_{A2} = V_{CC} \times \frac{R2 \parallel R3}{R1 + (R2 \parallel R3)}$$
 (2)

The equation below defines the total hysteresis provided by the network.

$$\Delta V_{A} = V_{A1} - V_{A2} \tag{3}$$

7.1.2.2 Non-Inverting Comparator With Hysteresis

A non-inverting comparator with hysteresis requires a two-resistor network and a voltage reference (V_{REF}) at the inverting input, as shown below.

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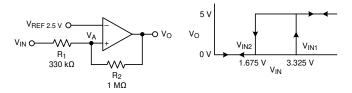


図 7-5. TLV351x in a Non-Inverting Configuration With Hysteresis

The equivalent resistor networks when the output is high and low are shown below.

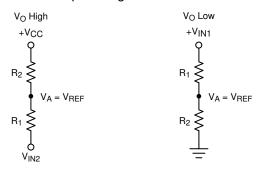


図 7-6. Non-Inverting Configuration Resistor Networks

When V_{IN} is less than V_{REF} , the output is low. For the output to switch from low to high, V_{IN} must rise above the V_{IN1} threshold. Use the equation below to calculate V_{IN1} .

$$V_{IN1} = R1 \times \frac{V_{REF}}{R2} + V_{REF} \tag{4}$$

When V_{IN} is greater than V_{REF} , the output is high. For the comparator to switch back to a low state, V_{IN} must drop below V_{IN2} . Use equation below to calculate V_{IN2} .

$$V_{IN2} = \frac{V_{REF} (R1 + R2) - V_{CC} \times R1}{R2}$$
 (5)

The hysteresis of this circuit is the difference between V_{IN1} and V_{IN2} , as shown below.

$$\Delta V_{IN} = V_{CC} \times \frac{R1}{R2}$$
 (6)

For more information, please see Application Notes SNOA997 "Inverting comparator with hysteresis circuit" and SBOA313 "Non-Inverting Comparator With Hysteresis Circuit".

7.2 Typical Applications

7.2.1 Low-Side Current Sensing

The figure below shows a simple low-side current sensing circuit using a high-speed comparator. Since this design does not utilze an amplifier, the response time is only limited by the propagation delay of the comparator. With faster response time, the design is well-suited for short-circuit detection when speed is more important than accuracy. When the voltage across the shunt resistor reaches the critical over-current threshold created by R1 and R2, the comparator output changes state.

Product Folder Links: TLV3511

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17

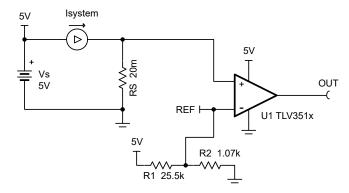


図 7-7. Current Sensing

7.2.1.1 Design Requirements

For this design, follow these design requirements:

- Alert (overcurrent) event occurs when system current (Isystem) reaches 10A
- Alert signal (OUT) is active high
- Operate from a 5V power supply

7.2.1.2 Detailed Design Procedure

To minimize power dissipation and voltage drop across the shunt resistor (RS), a value of $20m\Omega$ is selected. Since the overcurrent level of 10A creates a 200mV drop across RS, R1 and R2 are calculated to create the voltage divider value of 200mV from the regulated 5V supply voltage. If the system is expected to operate close to the 10A maximum, hysteresis can be added to the design as shown in Non-Inverting Comparator With Hysteresis.

7.2.1.3 Application Curve

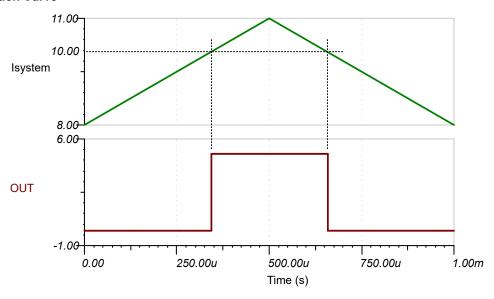


図 7-8. Current Sensing Results

7.3 Power Supply Recommendations

Due to the fast output edges, it is critical to have bypass capacitors on the supply pin to prevent supply ringing and false triggers and oscillations. Bypass the supply directly at *each* device with a low ESR 0.1µF ceramic bypass capacitor directly between the (V+) pin and ground pins. Narrow peak currents are drawn during the output transition time, particularly for the push-pull output device. These narrow pulses cause un-bypassed

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English Data Sheet: SNOSDJ9



supply lines and poor grounds to ring, possibly causing variation that limits the input voltage range and creates an inaccurate comparison or even oscillations.

The device is capable of being powered from both "split" supplies ((V+) & (V-)), or "single" supplies ((V+) and GND), with GND applied to the (V-) pin. Input signals must stay within the recommended input range for either type. Note that with a "split" supply the output now swings "low" (V_{OL}) to (V-) potential and not GND.

7.4 Layout

7.4.1 Layout Guidelines

For accurate comparator applications it is important to maintain a stable power supply with minimized noise and glitches. Output rise and fall times are in the tens of nanoseconds, and need to be treated as high speed logic devices. Place the bypass capacitor as close to the supply pin as possible and connect to a solid ground plane, directly between the (V+) and GND pins.

Minimize coupling between outputs and inputs to prevent output oscillations. Do not run output and input traces in parallel unless there is a (V+) or GND trace between output to reduce coupling. When series resistance is added to inputs, place resistor close to the device. A low value (<100 ohms) resistor added in series with the output dampens any ringing or reflections on long, non-impedance controlled traces. For best edge shapes, use controlled impedance traces with back-terminations when routing long distances.

7.4.2 Layout Example

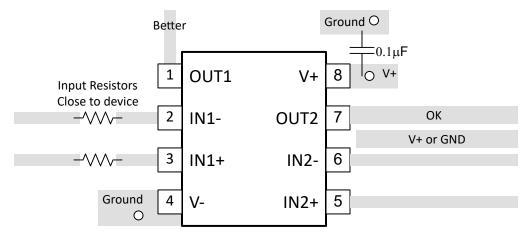


図 7-9. Dual Layout Example

8 Device and Documentation Support

8.1 Documentation Support

8.1.1 Related Documentation

Analog Engineers Circuit Cookbook: Amplifiers (See Comparators section) - SLYY137

Precision Design, Comparator with Hysteresis Reference Design— TIDU020

Window comparator circuit - SBOA221

Reference Design, Window Comparator Reference Design— TIPD178

Comparator with and without hysteresis circuit - SBOA219

Inverting comparator with hysteresis circuit - SNOA997

Non-Inverting Comparator With Hysteresis Circuit - SBOA313

A Quad of Independently Func Comparators - SNOA654



8.2 ドキュメントの更新通知を受け取る方法

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8.6 用語集

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9 Revision History

資料番号末尾の英字は改訂を表しています。その改訂履歴は英語版に準じています。

DATE	REVISION	NOTES
December 2024	*	Initial Release

10 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
TLV3511DCKR	ACTIVE	SC70	DCK	5	3000	RoHS & Green	SN	Level-1-260C-UNLIM	-40 to 125	1TH	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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OTHER QUALIFIED VERSIONS OF TLV3511:

PACKAGE OPTION ADDENDUM

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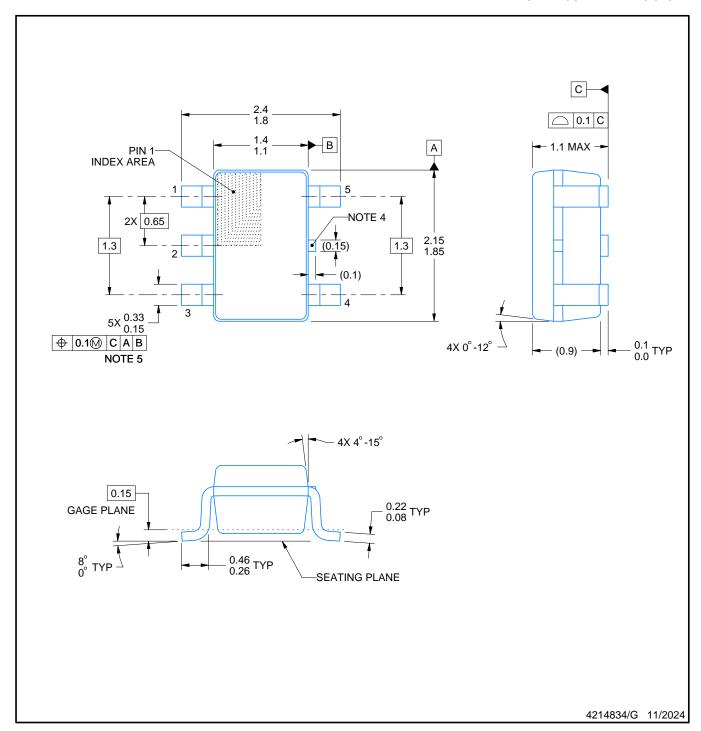
• Automotive : TLV3511-Q1

NOTE: Qualified Version Definitions:

• Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects



SMALL OUTLINE TRANSISTOR



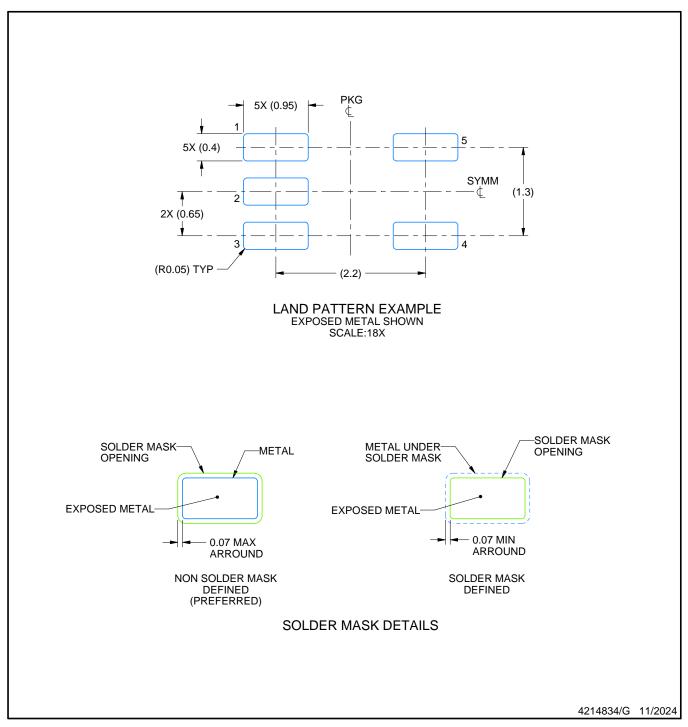
NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 2. This drawing is subject to change without notice.
 3. Reference JEDEC MO-203.

- 4. Support pin may differ or may not be present.5. Lead width does not comply with JEDEC.
- 6. Body dimensions do not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.25mm per side



SMALL OUTLINE TRANSISTOR

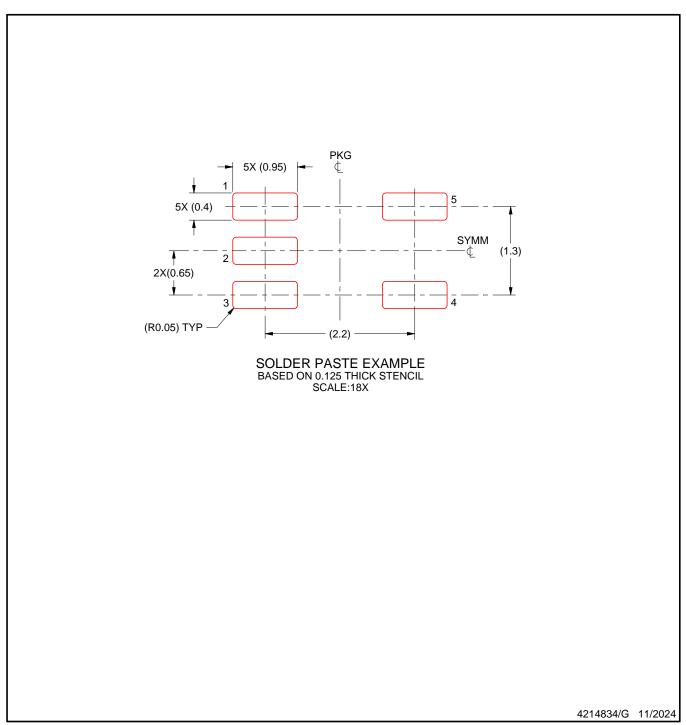


NOTES: (continued)

7. Publication IPC-7351 may have alternate designs.8. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE TRANSISTOR



NOTES: (continued)

- 9. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 10. Board assembly site may have different recommendations for stencil design.



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